

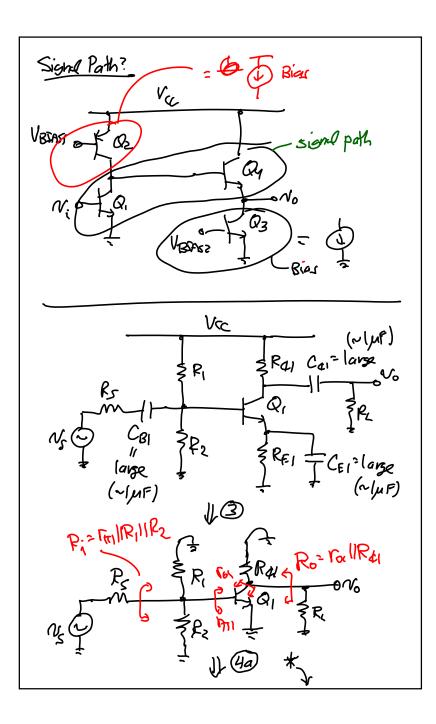
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<u>EE 140/240A</u>: Analog Integrated Circuits <u>Lecture 4w</u>: Inspection Analysis

Procedure:

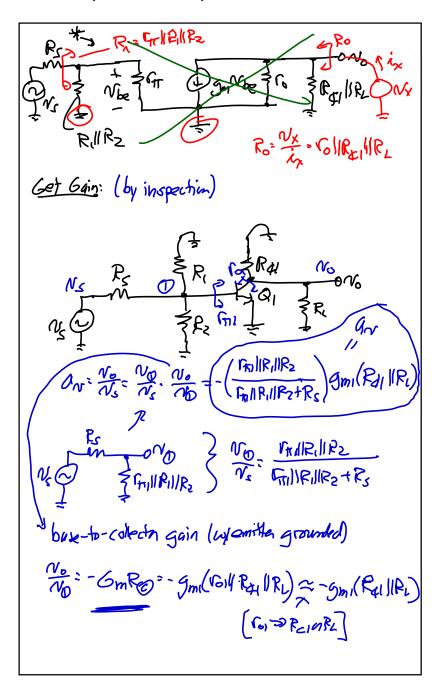
- 1. Find the DC operating point
 - Get all the voltages & currents at all nodes & branches, respectively
- 2. Determine S.S. parameters for devices in the signal path (e.g., g_m , r_π , r_o , ...)
- 3. Convert the full circuit to the S.S. circuit
 - Zero out DC sources
 - Short out large capacitors (e.g., with values greater than nF's)
- 4. (a) If needed, replace transistor with its S.S.
 model (e.g., hybrid-π, T-model, ...)
 - This should NOT be needed often!
 - When is it needed? → generally in cases where there is feedback

4. (b) Analyze by inspection based on prior S.S. analysis experience! (This should be 99% of the time.)



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Ex. Common-Collector B= Jnl(GIIPE) ~ Jn)PE N' O $R_{E} = \frac{V_{0}}{V_{1}} \frac{R_{E}}{CetR_{E}} \frac{(Bt)!}{\Gamma rt}$ $R_{e}^{-1} \Gamma rt (Bt)!R_{E} = \frac{1}{T} \Gamma rt$